

Supporting Information

Organobismuth Molecular Crystals for Organic Topological Insulators

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1: General Experimental Information

All reagents were purchased from Tokyo chemical industry (TCI) and used without further purification. TGA spectra were obtained to confirm the vaporization temperature of organobismuth molecules using a thermogravimetric analyzer (TGA, SCINCO model no.1000). Also, the morphologies of the product crystals were characterized by SEM (JSM-7410F, JEOL) at National Institute for Nanomaterials Technology (NINT) in Pohang. The PL images and signals were obtained using a fluorescence microscope (Olympus microscope) and spectrometer (SpectraPro, Princeton Instruments) equipped with a filter set (Exciter BP 330 – 380 nm; beam splitter 400 nm; Emitter LP 410 nm, Semrock).

2: Syntheses

Synthesis of organobismuth (TPB, o-TTB, p-TTB) crystals using PVT method : A small amount of organobismuth precursor powder was located at the center of a heating furnace with a protection quartz tube, and a piece of SiO₂/Si substrate was attached at the end of furnace to collect resulting crystals. the quartz tube was flushed using pure argon gas (99.999 %) at a flow rate of 100 sccm for 30 min. Under argon atmosphere, the temperature was gradually increased from room temperature to 150 °C, 170 °C , 145 °C for **TPB**, **o-TTB** and **p-TTB**, respectively. During the crystallization, the flow rate of argon gas was maintained as 50 sccm. After 1 h, big, white and wire-shaped crystals were obtained on the SiO₂/Si substrate.

Synthesis of organobismuth (TPB, o-TTB, p-TTB) crystals in solution phase:

- (1) Drop-drying method : Acetonitrile was used as a solvent to dissolve **TPB**, **p-TTB** and **o-TTB** precursors respectively. The concentration was controlled to be 1 mg/mL. After 10

minute sonication, a small aliquot of the final solution was dropped on SiO₂/Si substrate and dried under ambient condition.

(2) Solvent-vapor annealing method : 10 mL of acetonitrile was added in the 70 mL vial. To avoid contact between precursor solutions and pre-loaded acetonitrile solvent, pillar was placed inside the 70 mL vial on which precursor solution which are identical with that of drop-drying method was dropped on a SiO₂/Si substrate, respectively. After 12 h, fully dried the samples were carefully taken out of the vial.

3: Single crystal X-ray structure determination

The X-ray diffraction data for **TPB**, **p-TTB** and **o-TTB** were recorded on an ADSC Q210 CCD area detector with a synchrotron radiation ($\lambda = 0.63000 \text{ \AA}$) at 2D beamline in Pohang Accelerator Laboratory (PAL). The diffraction images were processed by using HKL3000.¹ Absorption correction was performed by using the program PLATON.² The structure was solved by ShelXT³ using Intrinsic Phasing and refined by ShelXL.⁴ All the non-hydrogen atoms were refined anisotropically. All hydrogen atoms were added to their geometrically ideal positions.

Triphenyl bismuth (**TPB** C₁₈H₁₅Bi₁, Mr = 440.28, crystal dimensions $0.36 \times 0.05 \times 0.01 \text{ mm}^3$, monoclinic, C2/C, $a = 27.486(6) \text{ \AA}$, $b = 5.7130(11) \text{ \AA}$, $c = 20.248(4) \text{ \AA}$, $\beta = 114.25(3)^\circ$ $V = 2898.9(12) \text{ \AA}^3$, $T = -173 \text{ }^\circ\text{C}$, $Z = 8$, $r_{\text{calcd}} = 1.852 \text{ g cm}^{-3}$, $m = 8.89 \text{ mm}^{-1}$, 5559 unique reflections out of 5435 with $I > 2\sigma(I)$, 172 parameters, $1.44^\circ < \theta < 29.85^\circ$, $R1 = 0.0287$, $wR2 = 0.0999$, GOF = 0.918. (Reported CCDC deposit number: 111762)

Tri-p-tolyl-bismuthine (**p-TTB**): C₂₁H₂₁Bi₁, Mr = 481.35, crystal dimensions $0.50 \times 0.10 \times 0.05 \text{ mm}^3$, triclinic, $P-1$, $a = 6.3570(13) \text{ \AA}$, $b = 10.463(2) \text{ \AA}$, $c = 13.921(3) \text{ \AA}$, $\alpha = 91.70(3)^\circ$ $\beta = 91.54(3)^\circ$ $\gamma = 107.56(3)^\circ$, $V = 881.8(3) \text{ \AA}^3$, $T = -173 \text{ }^\circ\text{C}$, $Z = 2$, $r_{\text{calcd}} = 1.813 \text{ g cm}^{-3}$, $m = 7.31 \text{ mm}^{-1}$, 6081

unique reflections out of 5164 with $I > 2s(I)$, 202 parameters, $2.18^\circ < \theta < 29.87^\circ$, $R_1 = 0.0541$, $wR_2 = 0.1363$, GOF = 0.967. (Reported CCDC deposit number: 1115925)

Tri-*o*-tolyl-bismuthine (**o-TTB**): $C_{21}H_{20}Bi_1$, $M_r = 482.36$, crystal dimensions $0.18 \times 0.01 \times 0.007$ mm³, triclinic, $P-1$, $a = 5.111(1)$ Å, $b = 10.198(2)$ Å, $c = 16.588(3)$ Å, $\alpha = 91.16(3)^\circ$, $\beta = 95.53(3)^\circ$, $\gamma = 95.27(3)^\circ$, $V = 856.6(3)$ Å³, $T = -173^\circ\text{C}$, $Z = 2$, $r_{\text{calcd}} = 1.870$ g cm⁻³, $m = 9.831$ mm⁻¹, 4686 unique reflections out of 4473 with $I > 2s(I)$, 202 parameters, $1.12^\circ < \theta < 29.93^\circ$, $R_1 = 0.0525$, $wR_2 = 0.1478$, GOF = 0.947. (Reported CCDC deposit number: 1005303)

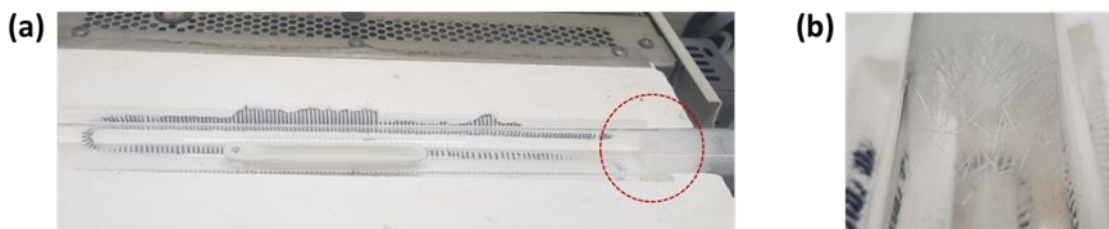


Figure S1. Photographs of obtained **TPB** crystals without SiO₂/Si substrate. (a) overall experimental setup after finishing the reaction (b) magnified view of the region where **TPB** crystals are grown in the quartz tube.

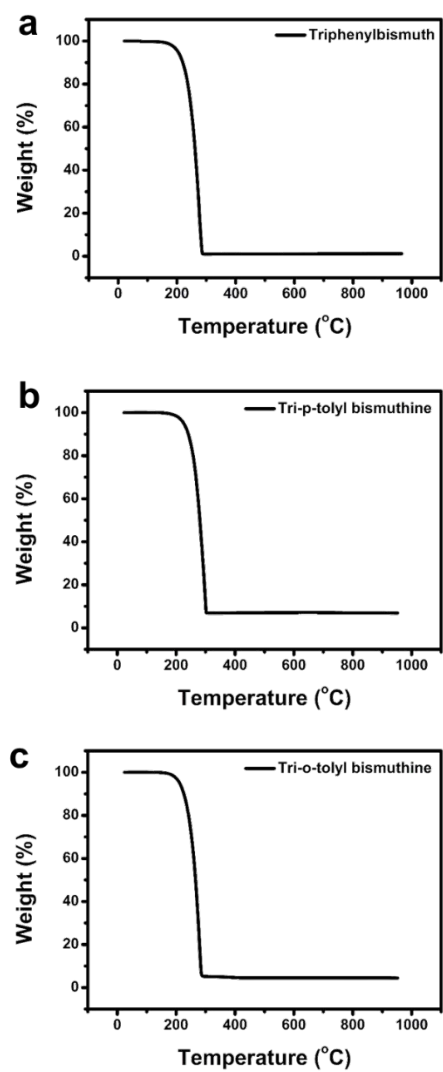


Figure S2. TGA results for **TPB** (a), **p-TTB** (b), and **o-TTB** (c) powder.

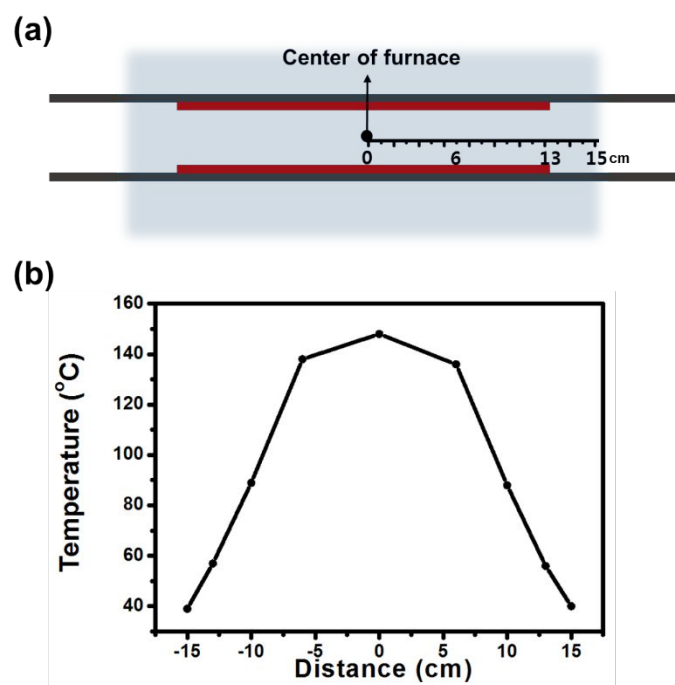


Figure S3. (a) Scheme of the furnace to indicate the distance from the center of furnace (b) measured temperature of each part of the furnace.

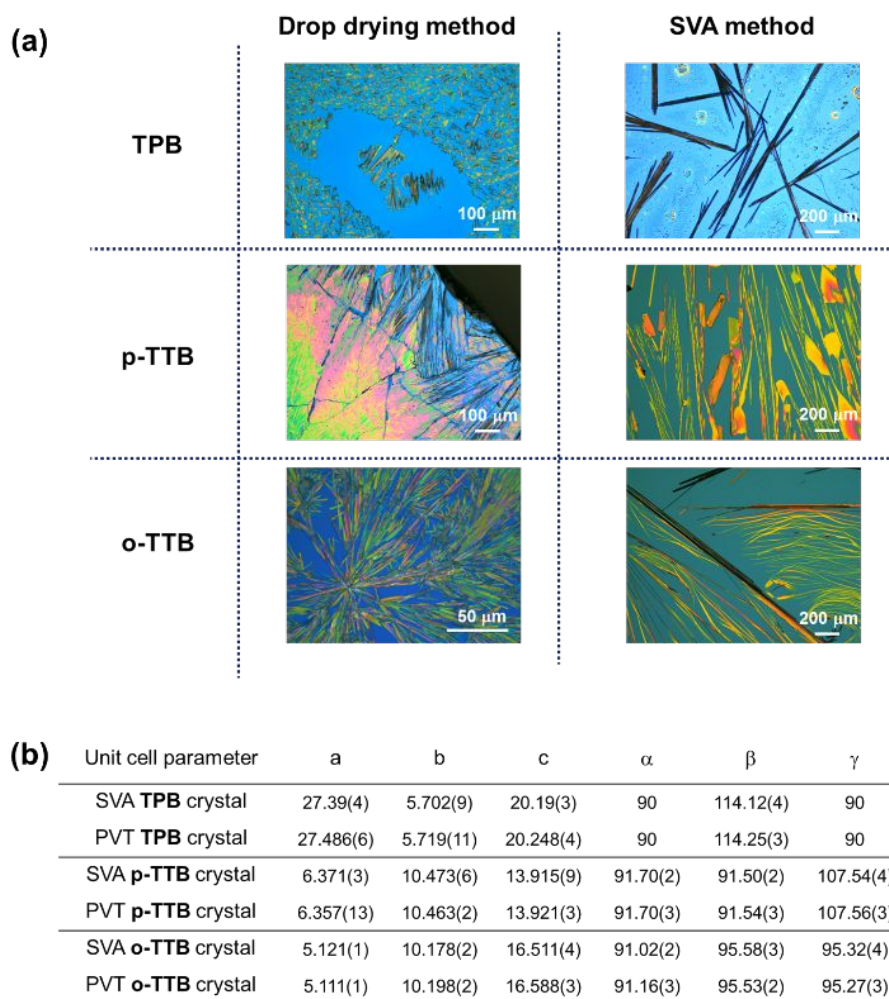


Figure S4. (a) Obtained **TPB**, **p-TTB** and **o-TTB** crystals using drop drying and solvent vapor annealing method (b) crystal structure information of **TPB**, **p-TTB** and **o-TTB** crystals grown by SVA and PVT method.

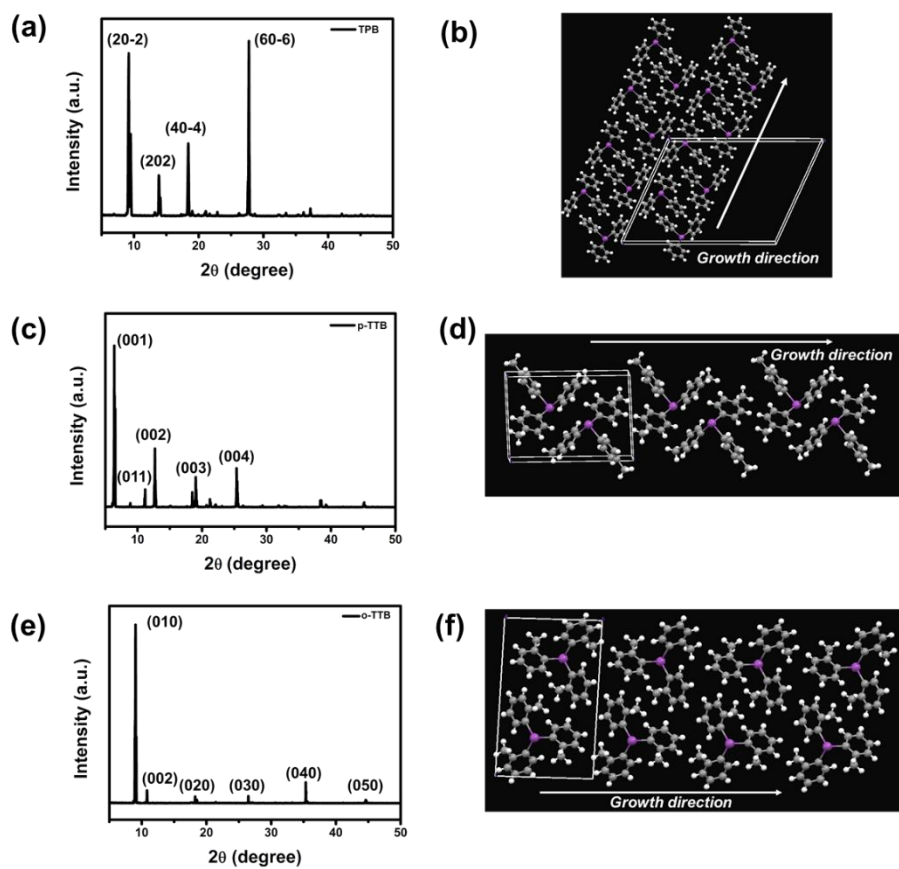


Figure S5. PXRD analysis and molecular packing structure according to the crystal growth direction (a,b) **TPB**, (c,d) **p-TTB** and (e,f) **o-TTB**.

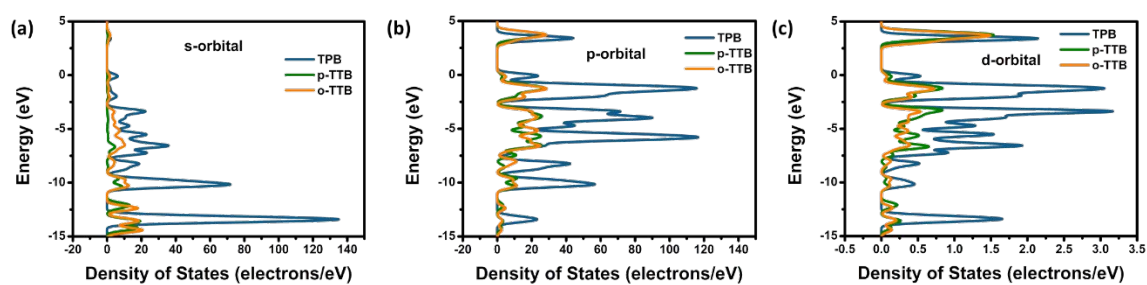


Figure S6. Calculated partial DOS of three organobismuth crystals. (a) s-orbital, (b) p-orbital, and (c) d-orbital contribution in DOS of each crystal.

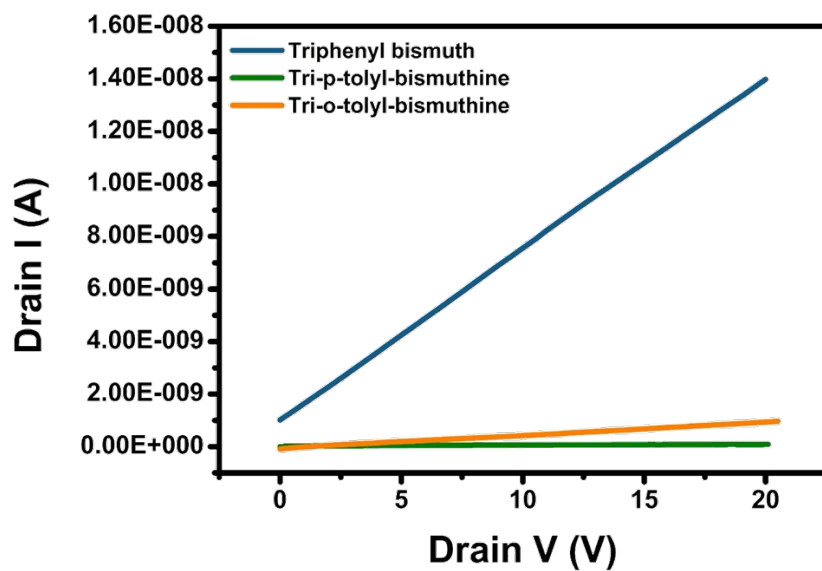


Figure S7. I-V characteristic curves of **TPB** (blue), **p-TTB** (green) and **o-TTB** (orange) crystals grown by PVT process. The devices were prepared on a SiO_2/Si substrate using silver paste as source and drain electrodes.

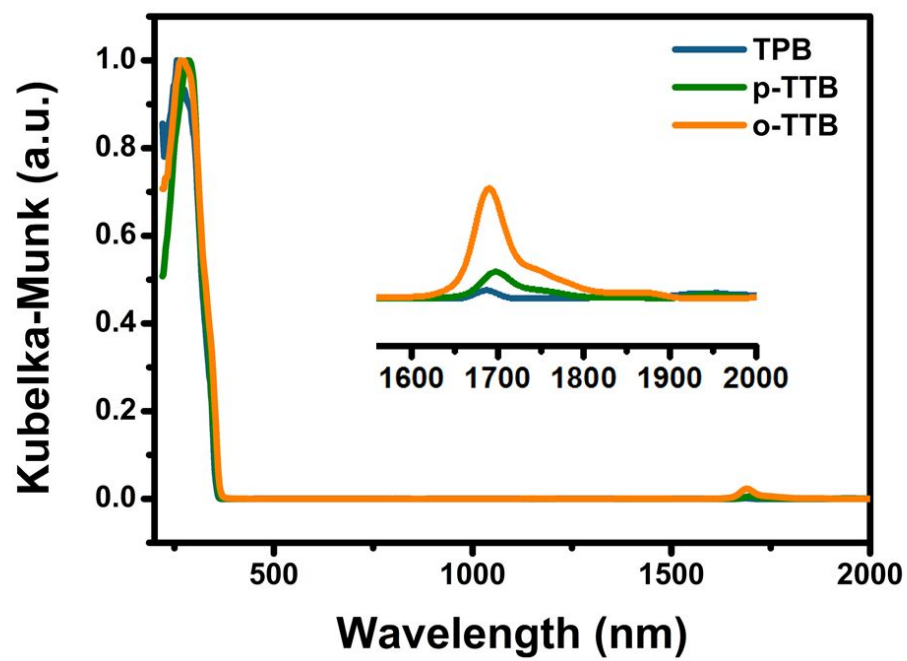


Figure S8. UV-VIS-NIR absorption spectra of **TPB**, **p-TTB** and **o-TTB** crystals.

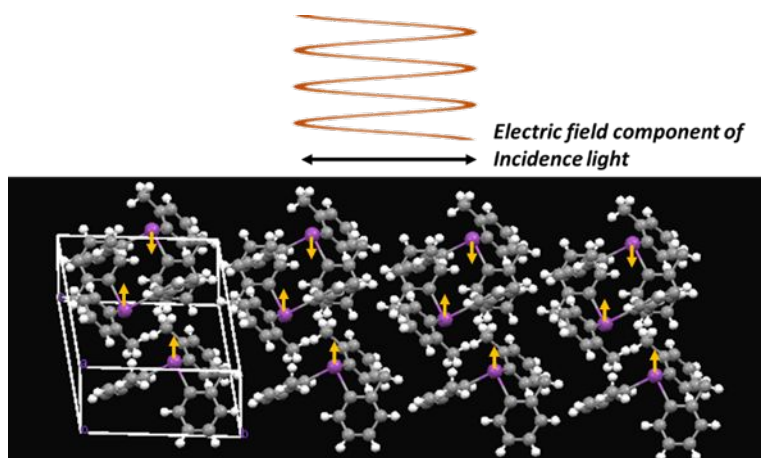


Figure S9. Interaction between the electric field of incident light and the dipole moment of (010) plane of the obtained **o-TTB** crystal

References

- 1) Otwinowski Z.; Minor, W. *Methods Enzymol.*, Processing of X-ray Diffraction Data Collected in Oscillation Mode **1997**, 276, 307-326.
- 2) Spek, A. L. *Acta Crystallogr. D*, **2009**, 65, 148-155.
- 3) Sheldrick, G. M. University of Göttingen, Germany, 1996.
- 4) Sheldrick, G. M. *Acta Crystallogr. A*, **2008**, A64, 112-122.